

ON Semiconductor®

# FQA9N90-F109

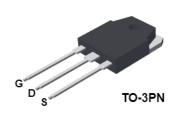
# N-Channel QFET® MOSFET 900 V, 8.6 A, 1.3 $\Omega$

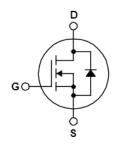
#### **Features**

- 8.6 A, 900 V,  $R_{DS(on)} = 1.3 \Omega$  (Max.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 4.3 \text{ A}$
- · Low Gate Charge (Typ. 55 nC)
- · Low Crss (Typ. 25 pF)
- · 100% Avalanche Tested
- · RoHS Compliant

# Description

This N-Channel enhancement mode power MOSFET is produced using ON Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.





## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter		FQA9N90-F109	Unit	
V <sub>DSS</sub>	Drain-Source Voltage		900	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		8.6	А	
	- Continuous (T <sub>C</sub> = 100°C)		5.45	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	34.4	А	
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note		900	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	8.6	А	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	24	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.0	V/ns	
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C)		240	W	
	- Derate Above 25°C		1.92	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C	

## **Thermal Characteristics**

Symbol	Parameter	FQA9N90-F109	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.52	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	°C/W

# **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQA9N90-F109	FQA9N90	TO-3PN	Tube	N/A	N/A	50 units

# Electrical Characteristics T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	teristics					l
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ = 0 V, $I_{D}$ = 250 $\mu$ A	900			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		1.0		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 900 V, V <sub>GS</sub> = 0 V			10	μА
		V <sub>DS</sub> = 720 V, T <sub>C</sub> = 125°C			100	μА
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Charac	teristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.3 A		1.0	1.3	Ω
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 4.3 A		9.2		S
Dynamic C	haracteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,		2100	2700	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		200	260	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			25	33	pF
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 450 V, I <sub>D</sub> = 8.6 A,		45	100	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		100	210	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			135	280	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)		80	170	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 720 V, I <sub>D</sub> = 8.6 A, V <sub>GS</sub> = 10 V		55	72	nC
Q <sub>gs</sub>	Gate-Source Charge			12		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4)		26		nC
Drain-Sour	rce Diode Characteristics and Maximum Rati	ngs				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				8.6	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				34.4	А
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 8.6 A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 8.6 A,		720		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> / dt = 100 A/μs		7.6		цС

#### NOTES

- 1. Repetitive rating : pulse-width limited by maximum junction temperature.
- 2. L = 23 mH,  $I_{AS}$  = 8.6 A,  $V_{DD}$  = 50 V,  $R_{G}$  = 25  $\Omega$ , starting  $T_{J}$  = 25°C.
- 3.  $I_{SD} \le 8.6 \text{ A}$ ,  $di/dt \le 200 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le BV_{DSS}$ , starting  $T_J = 25^{\circ}\text{C}$ .
- Essentially independent of operating temperature.

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

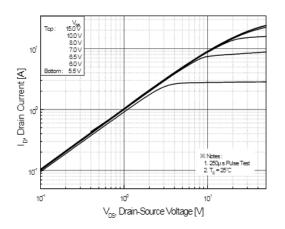


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

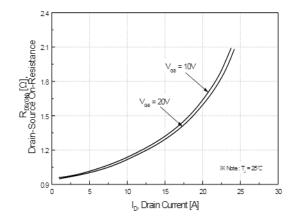


Figure 5. Capacitance Characteristics

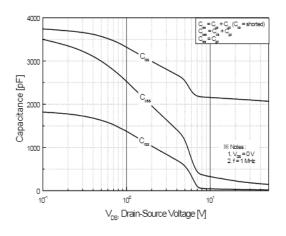


Figure 2. Transfer Characteristics

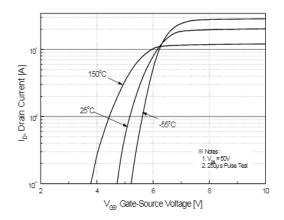


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

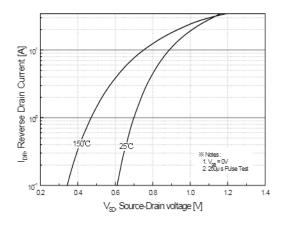
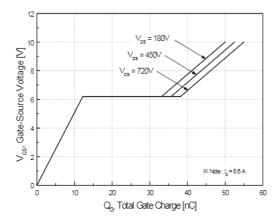


Figure 6. Gate Charge Characteristics



# Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

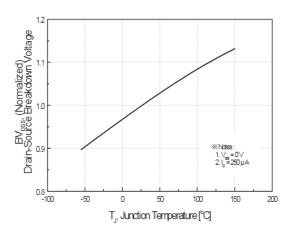


Figure 9. Maximum Safe Operating Area

Figure 8. On-Resistance Variation vs. Temperature

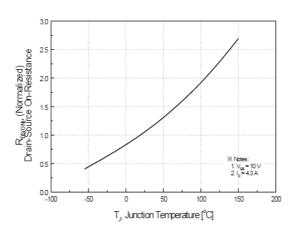


Figure 10. Maximum Drain Current vs. Case Temperature

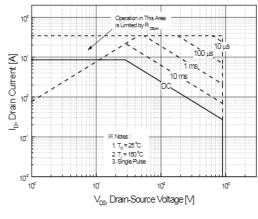
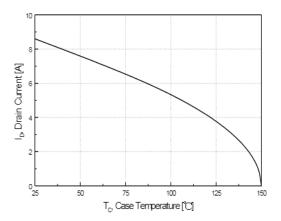
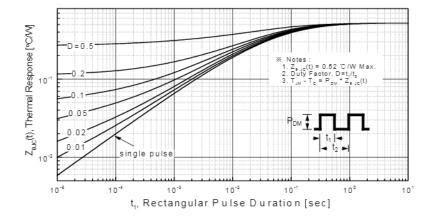


Figure 11. Transient Thermal Response Curve





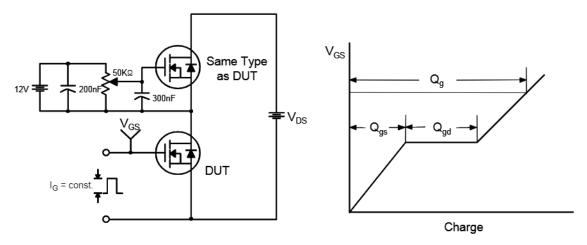


Figure 12. Gate Charge Test Circuit & Waveform

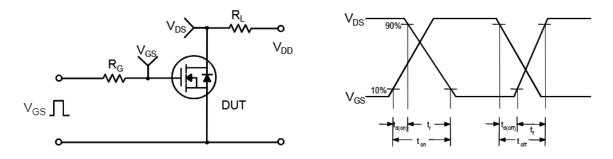


Figure 13. Resistive Switching Test Circuit & Waveforms

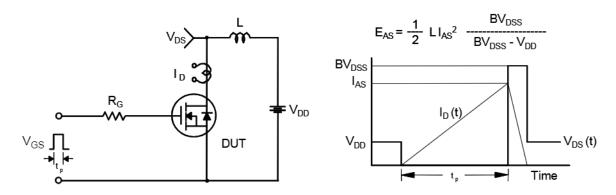


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

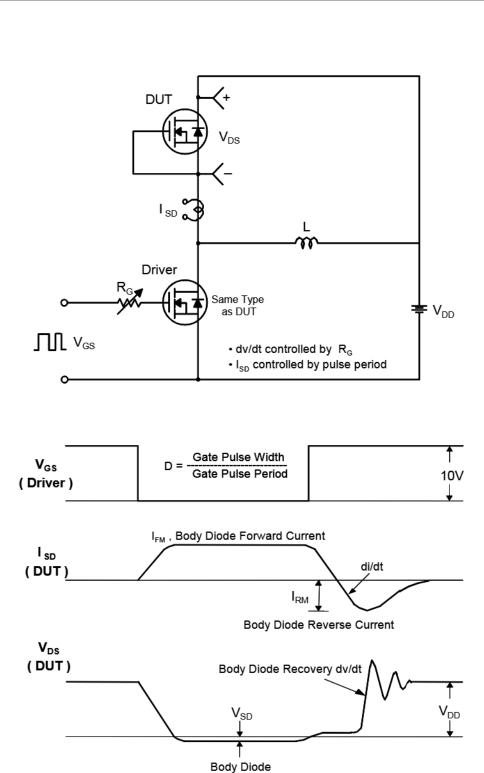
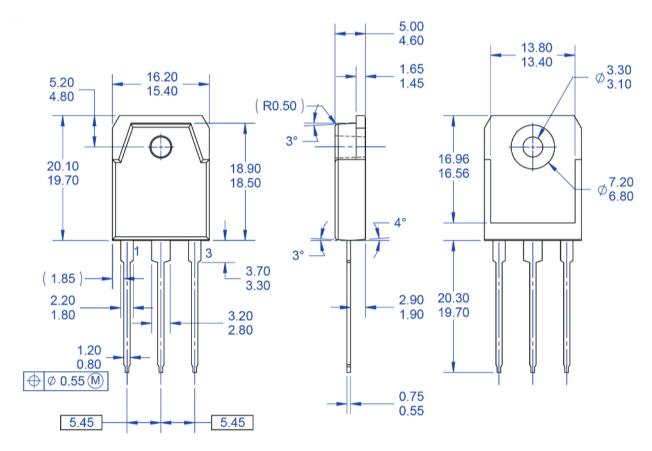
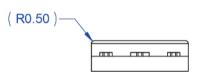


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

Forward Voltage Drop

## **Mechanical Dimensions**





### NOTES: UNLESS OTHERWISE SPECIFIED

- A) THIS PACKAGE CONFORMS TO EIAJ SC-65 PACKAGING STANDARD.
   B) ALL DIMENSIONS ARE IN MILLIMETERS.
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- **DIMENSION AND TOLERANCING PER** ASME14.5-2009.
- D) DIMENSIONS ARE EXCLUSSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSSIONS.
  E) DRAWING FILE NAME: TO3PN03AREV1.

Figure 16. TO3PN, 3-Lead, Plastic, EIAJ SC-65

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